Silicon NPN Phototransistor

Description

TEST2600 is a high sensitive silicon NPN epitaxial planar phototransistor in a miniature side view plastic package with cylindrical lens.

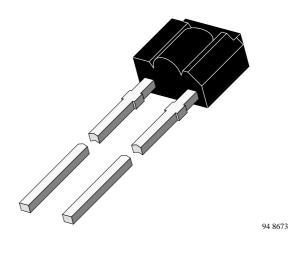
Its epoxy casting is designed as a infrared filter to spectrally match to GaAs IR emitters (λ_p =950nm).

Features

- High radiant sensitivity (2.5 mA)
- Miniature side view package with cylindrical lens
- Very wide viewing angle $\varphi = \pm 30^{\circ} / \pm 60^{\circ}$
- Suitable for near IR radiation
- Matches with TSSS 2600 IR emitter •

Applications

Optical switches Counters and sorters Interrupters Tape and card readers Encoders Position sensors



Absolute Maximum Ratings

 $T_{amb} = 25 \,^{\circ}C$

Parameter	Test Conditions	Symbol	Value	Unit
Collector Emitter Voltage		V _{CEO}	70	V
Emitter Collector Voltage		V _{ECO}	5	V
Collector Current		IC	50	mA
Peak Collector Current	$t_p/T = 0.5, t_p \le 10 \text{ ms}$	I _{CM}	100	mA
Total Power Dissipation	$T_{amb} \leq 55 \ ^{\circ}C$	P _{tot}	100	mW
Junction Temperature		Tj	100	°C
Storage Temperature Range		T _{stg}	-55+100	°C
Soldering Temperature	$t \leq 3 s, 2 mm$ from case	T _{sd}	260	°C
Thermal Resistance Junction/Ambient		R _{thJA}	450	K/W

Basic Characteristics

 $T_{amb} = 25^{\circ}C$

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
Collector Emitter Breakdown Voltage	$I_C = 1 mA$	V _{(BR)CEO}	70			V
Collector Dark Current	$V_{CE} = 20 V, E = 0$	I _{CEO}		1	100	nA
Collector Emitter Capacitance	$V_{CE} = 5 V, f = 1 MHz, E=0$	C _{CEO}		6		pF
Collector Light Current	$\begin{array}{l} E_e = 1 m W/cm^2, \ \lambda = 950 nm, \\ V_{CE} = 5 V \end{array}$	I _{ca}	1	2.5		mA
Angle of Half Sensitivity	horizontal	φ1		±30		deg
	vertical	φ2		±60		deg
Wavelength of Peak Sensitivity		$\lambda_{\rm p}$		920		nm
Range of Spectral Bandwidth		λ _{0.5}		850980		nm
Collector Emitter Saturation Voltage	$\begin{array}{l} E_e = 1 m W/cm^2, \ \lambda = 950 nm, \\ I_C = 0.1 m A \end{array}$	V _{CEsat}			0.3	V
Turn–On Time	$V_S=5V, I_C=5mA, R_L=100\Omega$	t _{on}		6		μs
Turn–Off Time	$V_S=5V$, $I_C=5mA$, $R_L=100\Omega$	t _{off}		5		μs
Cut–Off Frequency	$V_S=5V, I_C=5mA, R_L=100\Omega$	f _c		110		kHz

Typical Characteristics ($T_{amb} = 25^{\circ}C$ unless otherwise specified)

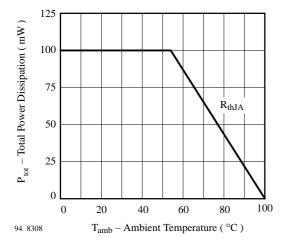


Figure 1. Total Power Dissipation vs. Ambient Temperature

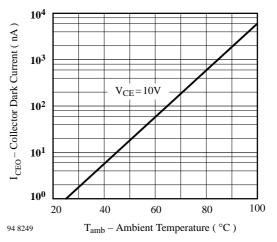


Figure 2. Collector Dark Current vs. Ambient Temperature





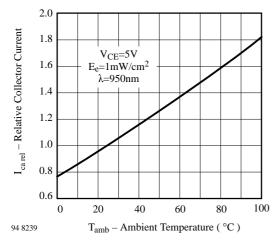


Figure 3. Relative Collector Current vs. Ambient Temperature

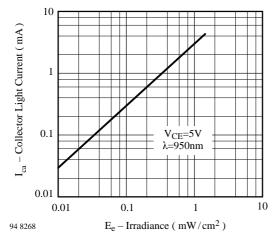


Figure 4. Collector Light Current vs. Irradiance

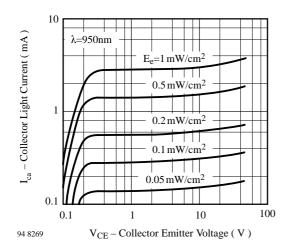
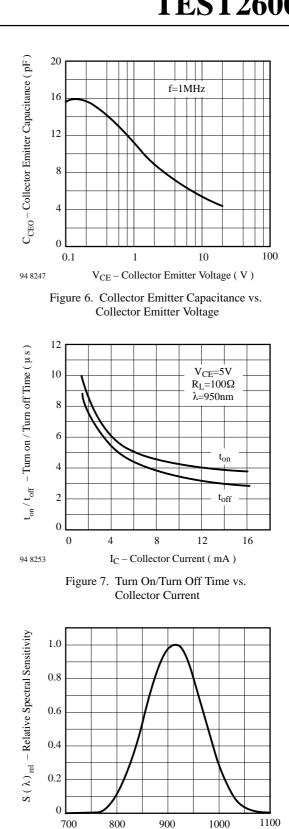


Figure 5. Collector Light Current vs. Collector Emitter Voltage





 λ – Wavelength (nm)

700

94 8270

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TEST2600

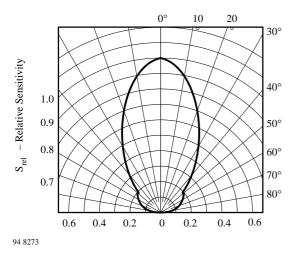
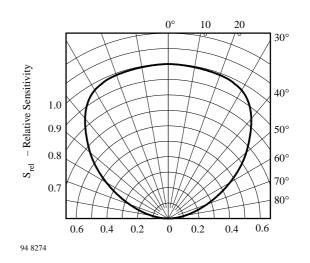
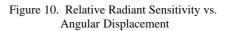


Figure 9. Relative Radiant Sensitivity vs. Angular Displacement

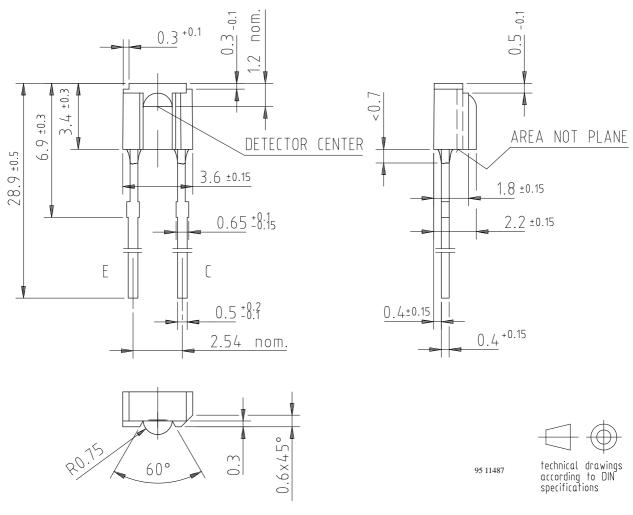


EMIC

Semiconductors



Dimensions in mm



Ozone Depleting Substances Policy Statement

It is the policy of **TEMIC TELEFUNKEN microelectronic GmbH** to

- 1. Meet all present and future national and international statutory requirements.
- 2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

TEMIC TELEFUNKEN microelectronic GmbH semiconductor division has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

- 1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
- 2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
- 3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

TEMIC can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

We reserve the right to make changes to improve technical design and may do so without further notice. Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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